

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/003,557	CHANG ET AL.	CHANG ET AL.	
Examiner	Art Unit	Art Unit	
Nhon T. Diep	2613	2613	

SEARCHED						
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East text search included	7/17/06	N.D	